



# Test Report

STMICRO ELECTRONICS  
20F, 207, TUN HUA SOUTH ROAD, SECTION 2,  
TAIPEI 106, TAIWAN

Report No. : CE/2004/C5150  
Date : 2005/01/04  
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The following merchandise was (were) submitted and identified by the client as :

Type of Product : IC  
Style/Item No : TO-220AB  
Sample Received : 2004/12/28  
Testing Date : 2004/12/28 TO 2005/01/04

## Test Result

PART NAME NO.1 : SILVER COLORED METAL PIN (PLEASE REFER TO THE PHOTO)  
PART NAME NO.2 : MIXED SILVER COLORED METAL/BLACK PLASTIC BODY (PLEASE REFER TO THE PHOTO ATTACHED)

Test Item (s):	Unit	Method	MDL	Result			
				No.1	No.2		
Chromium VI (Cr+6)	ppm	As per US EPA 7196A and US EPA 3060A.	2	N.D.	N.D.		
Cadmium (Cd)	ppm	ICP-AES after as per EN 1122, method B:2001 or other acid digestion.	2	N.D.	N.D.		
Mercury (Hg)	ppm	ICP-AES after as per US EPA 3052 or other acid digestion.	2	N.D.	N.D.		
Lead (Pb)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.	2	136.6	2841.9		

NOTE : (1) N.D. = Not detected (<MDL)  
(2) ppm = mg/kg  
(3) MDL = Method Detection Limit

  
Daniel Yeh, M.R. / Operation Manager  
Signed for and on behalf of  
SGS TAIWAN LTD.

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